

OTR screen development at CTF3



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Outline

- CLIC and CTF3
 - Beam characteristics, instrumentation requirements
 - Installed equipment
- OTR characteristics
- Studies done on OTR screen systems
 - Thermal/material studies
 - Screen shapes and surfaces
 - Other general improvements
- Planned studies
- Summary



CLIC and CTF3



- CLIC study for a future linear e⁺e⁻ collider based on two-beam acceleration: high intensity drive beam as RF power source for high energy main beam
- CTF3 The 3rd CLIC Test Facility for feasibility tests of the RF source: drive beam generation and deceleration, two-beam acceleration



CTF3 – The CLIC Test Facility



OTR properties

- OTR emitted when a charged particle goes from a medium to another with different dielectric properties.
- Radiation is emitted in forward and backward direction, of which the latter is generally used due to easier extraction.
- For ultra-relativistic particles:





Why OTR?

- Beam intensity: from 4 A during 1.4 μ s, to 32 A, 140 ns. Beam size ~1 mm, pulse repetition rate up to 5 Hz
 - Thermal load too high for scintillating screens
 - High intensity compensates for lower light yield
- Up to coherence, perfectly linear with beam charge (no saturation)
- Femto-second time resolution possible
 - Allows for longitudinal profile imaging (bunch length)
- Due to properties of the emitted light, it can be used to determine several beam properties.

OTR screen system at CTF3

"Standard" system (subject to local variations)



- 1. Tilted screen(s) inside a vacuum tank
- 2. View port, mirrors and achromat lenses
- 3. Filter wheel for light attenuation
- 4. CCD camera, digitization box.

Resolution 70-200 μ m.

Screen damages

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Spectrometer screen in PHIN the photoinjector test facility for CLIC

- "hot spots" on the screen observed even when the beam is not there
- A closer look at the screen shows clear damages
 - Reason? Most likely thermal load.

Thermal considerations

- CTF3 high intensity electron beam constitutes a high thermal load on intrusive devices even OTR screens.
- Solution: Thermally resistant materials as radiators, at the expense of total light intensity (reflectivity). Specific heat capacity, melting temperature, and thermal conductivity key properties.
- Intensified camera where necessary.
- Si, SiC and C tested successfully.



200 μ m foil thickness



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Screens for transverse profiling

Several improvements of the systems for transverse profile measurements:

- Screen beam angle 15° to minimize field depth errors
- Simpler design with view port at an angle, followed by mirror which directs the beam towards the CCD camera on the floor through a lens, filters for light attenuation, and another mirror.
- Special shielding designed for the camera radiation huge problem at CTF3.



Screen system with four different positions:

- **1.** Calibration target
- **2.** Highly reflective screen (Si)
- **3.** Less reflective, thermally resistant screen (SiC)
- **4.** Replacement chamber to reduce beam impedance while not in use.



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Screens for spectrometry



- All systems for spectrometry have fixed aluminum screens
- New standard: block synchrotron radiation using a carbon foil
- Extensive investigation on how to improve linearity of the complete system: relative amount of light reaching the camera decreases rapidly as the beam hits the edge (worse for high beam energy)

Parabolic screen





E. Bravin, T. Lefevre, C.P. Welsch

- An initial focusing of the light reduces vignetting effects on the screen edges.
- Screen support with parabolic shape: $y = \frac{x^2}{f}$

where f is distance to the first lens.



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Diffusive screen

120

100

80

-15

-40

-20

relative intensity (%)

- Intentional (and controlled!) reduction of the screen reflectivity can minimize non-linear effects in the system due to vignetting in lenses.
- Non-blanc surface increases angular divergence of OTR emission same amount of light reaches the camera independent on beam position on screen.

Intensity during a scan over the screen:



60 40 20 -20-40-20 20 0 40 x (mm)15 Al screen, diffusive 10 -5 -10⊳

0

x (mm)

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20

40

Al screen, diffusive

OTR for low energy e

- For low energy, OTR emission highly asymmetric. Camera at an angle to catch the most intense part.
- Place camera not in image plane to capture angular distribution of OTR emission: possible to determine beam divergence and energy.





What's next?

- Extrapolate from CTF3 to CLIC parameters
 - Drive Beam: higher energy, higher intensity, larger energy spread
 - Main beam: higher energy, smaller beam size, shorter bunches
- Error in size/emittance due to energy spread?
- Develop cheap and robust systems

Large energy spread beams

- The beam in the CLIC Drive Beam decelerator will go from initial energy 2.4 GeV to 0.24 GeV (90 % energy extraction), with a large intra-bunch energy spread.
- Test Beam Line (TBL) at CTF3 a small-scale test of the CLIC decelerator.
- To be investigated: how "wrong" we measure transverse profile using standard OTR screens.



Summary

- OTR screens important tool in everyday operation of CTF3
 - Enough light intensity, better for high intensity beams.
- Improvement of the overall performance of the OTR screen systems
 - Thermally resistant materials as radiators increase life time
 - Parabolic and diffusive screens recovers performance losses when going to higher beam energy and improves reliability of energy measurement
- Next step: focus on OTR based diagnostics for beams of large energy spread



Further reading:

- Optimization of OTR screen surface materials and OTR screen geometry at CTF3, C.P. Welsch et al.
- OTR studies for the high charge CTF3 beam, E. Bravin et al.
- Studies of OTR angular distribution at CTF2, E. Bravin et al.
- CTF3 Injector Profile Monitor, C. Bal, et al.

